

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Kazunobu MIKI

Serial No.: 09/973,049

Filed: October 10, 2001

Group Art Unit: 2829

Examiner: J. M. Hollington

For: SEMICONDUCTORELEMENT TEST APPARATUS, AND METHOD OF TESTING
SEMICONDUCTORELEMENT USING THE APPARATUS

THE COMMISSIONER FOR PATENTS AND TRADEMARKS
Washington, DC 20231

Dear Sir:

Transmitted herewith is an Amendment in the above identified application.



No additional fee is required.

Applicant is entitled to small entity status under 37 CFR 1.27

Also attached:

The fee has been calculated as shown below:

	NO. OF CLAIMS	HIGHEST PREVIOUSLY PAID FOR	EXTRA CLAIMS	RATE	FEE
Total Claims	10	20	0	\$18.00 =	\$0.00
Independent Claims	3	3	0	\$84.00 =	\$0.00
Multiple claims newly presented					\$0.00
Fee for extension of time					\$0.00
					\$0.00
Total of Above Calculations					\$0.00

Please charge my Deposit Account No. 500417 in the amount of \$0.00. An additional copy of this transmittal sheet is submitted herewith.

The Commissioner is hereby authorized to charge payment of any fees associated with this communication or credit any overpayment, to Deposit Account No. 500417, including any filing fees under 37 CFR 1.16 for presentation of extra claims and any patent application processing fees under 37 CFR 1.17.

Respectfully submitted,

MCDERMOTT WILL & EMERY

Scott D. Paul

Registration No. 42,984

600 13th Street, N.W.
Washington, DC 20005-3096
(202) 756-8000 SDP:kap
Facsimile: (202) 756-8087
Date: March 4, 2003

RECEIVED
MAR -5 2003
TECHNOLOGY CENTER 2800





Docket No.: 50090-443

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of :
Kazunobu MIKI :
Application No.: 09/973,049 : Group Art Unit: 2829
Filed: October 10, 2001 : Examiner: Jermele M. Hollington
For: SEMICONDUCTOR ELEMENT TEST APPARATUS, AND
METHOD OF TESTING SEMICONDUCTOR ELEMENT
USING THE APPARATUS

77B Audit
J. Benson
3/6/03

RECEIVED
MAR - 5 2003
TECHNOLOGY CENTER 2800

AMENDMENT

Box Non-Fee Amendment
The Commissioner for Patents and Trademarks
Washington, DC 20231

Sir:

The following Amendment and Remarks are submitted in response to the Office Action
dated December 4, 2002. Please amend the above-identified application as follows:

IN THE SPECIFICATION:

Page 2, first full paragraph, please delete in its entirety and replace with the following:

--Fig. 11 is a side view showing the constitution of the prober 2 while the stage 4 remains in a lowered position. Fig. 12 is a perspective view showing a probe card 1 having the probe needles 7 mounted thereon. Fig. 13 is a top view showing the probe card 1. The prober 2 is equipped with the probe card 1. The probe card 1 has a probe card substrate 12 which supports the plurality of probe needles 7. The prober 2 has a test head 10 which operates in cooperation